

Automotive Dual P-Channel 30 V (D-S) 175 °C MOSFET

DESCRIPTION

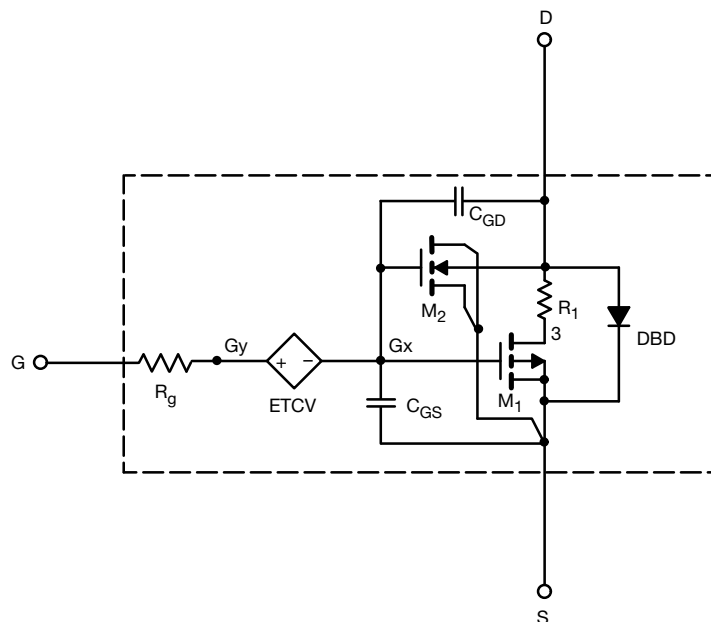
The attached SPICE model describes the typical electrical characteristics of the p-channel vertical DMOS. The subcircuit model is extracted and optimized over the -55 °C to +125 °C temperature ranges under the pulsed 0 V to 10 V gate drive. The saturated output impedance is best fit at the gate bias near the threshold voltage.

A novel gate-to-drain feedback capacitance network is used to model the gate charge characteristics while avoiding convergence difficulties of the switched C_{gd} model. All model parameter values are optimized to provide a best fit to the measured electrical data and are not intended as an exact physical interpretation of the device.

CHARACTERISTICS

- P-channel vertical DMOS
- Macro model (subcircuit model)
- Level 3 MOS
- Apply for both linear and switching application
- Accurate over the -55 °C to +125 °C temperature range
- Model the gate charge

SUBCIRCUIT MODEL SCHEMATIC



Note

- This document is intended as a SPICE modeling guideline and does not constitute a commercial product datasheet. Designers should refer to the appropriate datasheet of the same number for guaranteed specification limits



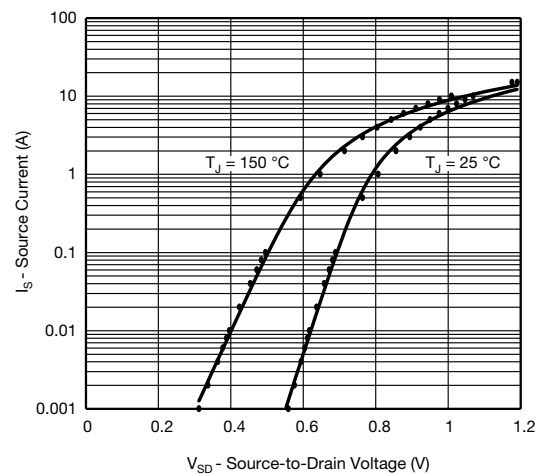
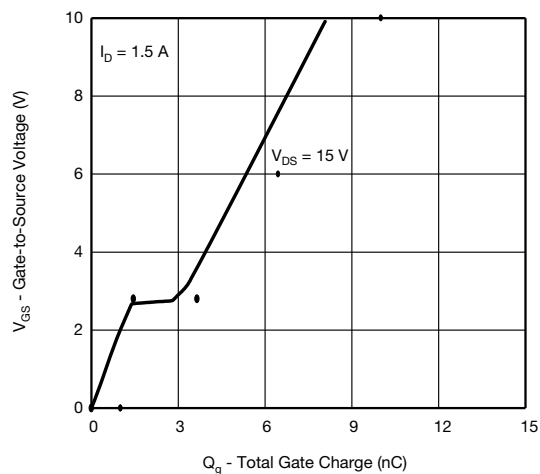
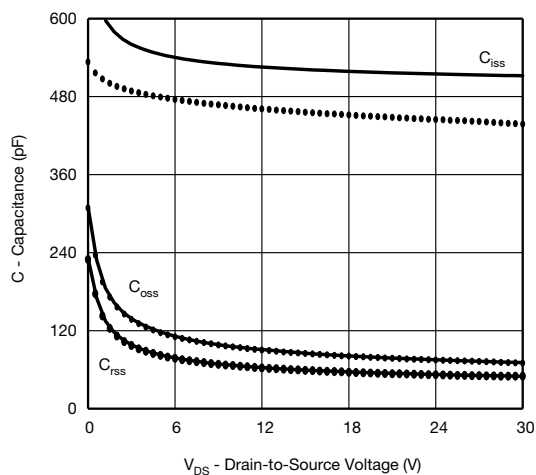
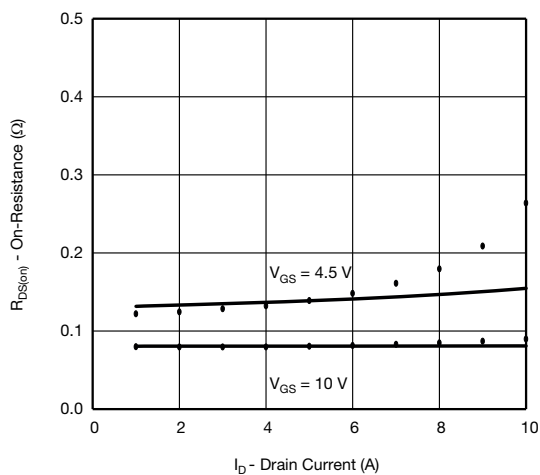
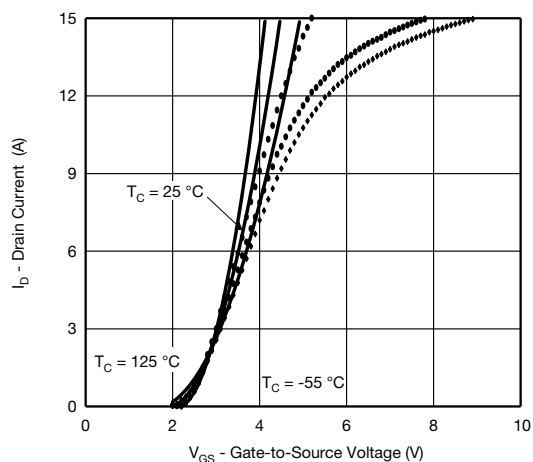
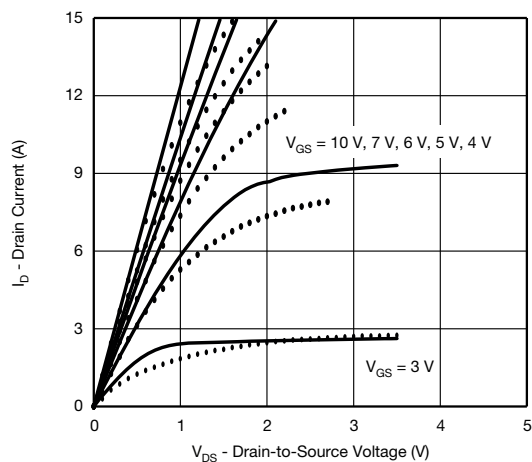
| SPECIFICATIONS ($T_J = 25\text{ }^{\circ}\text{C}$, unless otherwise noted) | | | | | |
|--|--------------|---|----------------|---------------|----------|
| PARAMETER | SYMBOL | TEST CONDITIONS | SIMULATED DATA | MEASURED DATA | UNIT |
| Static | | | | | |
| Gate-source threshold voltage | $V_{GS(th)}$ | $V_{DS} = V_{GS}$, $I_D = -250\text{ }\mu\text{A}$ | 2 | - | V |
| Drain-source on-state resistance ^a | $R_{DS(on)}$ | $V_{GS} = -10\text{ V}$, $I_D = -2\text{ A}$ | 0.081 | 0.085 | Ω |
| | | $V_{GS} = -4.5\text{ V}$, $I_D = -1.5\text{ A}$ | 0.131 | 0.135 | |
| Forward transconductance ^a | g_{fs} | $V_{DS} = -5\text{ V}$, $I_D = -1\text{ A}$ | 3 | 4.2 | S |
| Diode forward voltage | V_{SD} | $I_S = -0.5\text{ A}$ | -0.80 | -0.83 | V |
| Dynamic ^b | | | | | |
| Input capacitance | C_{iss} | $V_{DS} = -15\text{ V}$, $V_{GS} = 0\text{ V}$, $f = 1\text{ MHz}$ | 522 | 456 | pF |
| Output capacitance | C_{oss} | | 85 | 85 | |
| Reverse transfer capacitance | C_{rss} | | 59 | 59 | |
| Total gate charge | Q_g | $V_{DS} = -15\text{ V}$, $V_{GS} = -10\text{ V}$, $I_D = -3\text{ A}$ | 8.4 | 9.7 | nC |
| Gate-source charge | Q_{gs} | | 1.3 | 1.3 | |
| Gate-drain charge | Q_{gd} | | 2 | 2 | |

Notes

- a. Pulse test; pulse width $\leq 300\text{ }\mu\text{s}$, duty cycle $\leq 2\text{ }\%$
b. Guaranteed by design, not subject to production testing



COMPARISON OF MODEL WITH MEASURED DATA ($T_J = 25^\circ\text{C}$, unless otherwise noted)



Note

- Dots and squares represent measured data

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